

<b>INFORMATION DISCLOSURE STATEMENT PTO-1449</b>	Atty. Docket No. 021557A	Serial No. New Divisional Appln.
	Applicant(s): Naoya SASHIDA	
	Filing Date: October 31, 2003	Group Art Unit: 2814 (expected)

### U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Name	Date	Class	Subclas s	Filing Date (If appropriate)
<i>TY</i>	AA 2002/0006674 A1	Ma et al.	01/17/02	438	3	
<i>JH</i>	AB 6,570,203	Hikosaka et al.	05/2003	257	295	
<i>Vt</i>	AC 6,171,970	Xing et al.	01/2001	438	706	
	AD					
	AE					
	AF					
	AG					
	AH					

### FOREIGN PATENT DOCUMENTS

	Document No..	Date	Country	Translation (Yes or No)
<i>JY</i>	AI 2001-210798	08/03/01	Japan	Abstract
	AJ			
	AK			

### OTHER DOCUMENTS

	AL	
	AM	
Examiner		Date Considered <i>7/26/06</i>



<b>INFORMATION DISCLOSURE CITATION PTO-1449</b>	Atty. Docket No. 021557A	Serial No. 10/697,944
Applicant(s): SASHIDA, Naoya		
Filing Date: October 31, 2003	Group Art Unit: 2811	

### U.S. PATENT DOCUMENTS

Examiner Initial		Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
<i>TJ</i>	AA	6,121,648	Evans, Jr.	9/19/00	257	295	
<i>TJ</i>	AB	6,201,271	Okutoh et al.	3/13/01	257	295	
<i>TJ</i>	AC	2002/0021544	Cho et al.	2/21/02	361	200	
<i>TJ</i>	AD	6,211,035	Moise et al.	4/3/01	438	396	
<i>TJ</i>	AE	2002/0127867	Lee	9/12/02	438	694	

### FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Translation (Yes or No)
<i>TJ</i>	AF EP 1 189 262 A2	3/20/02	European	Yes
	AG			
	AH			

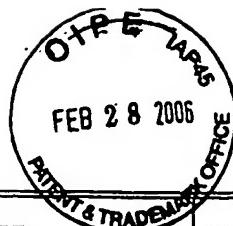
### OTHER DOCUMENTS

<i>TJ</i>	AI	SAKODA T. ET AL: "HYDROGEN-ROBUST SUBMICRON IROX/PB (ZR,TI) 03/IR CAPACITORS FOR EMBEDDED FERROELECTRIC MEMORY" JAPANESE JOURNAL OF APPLIED PHYSICS, PUBLICATION OFFICE JAPANESE JOURNAL OF APPLIED PHYSICS. TOKYO, JP, vol. 40, no. 4B, PART 1, April 2001 (2001-04), pages 2911-2916, XPOO1081007 ISSN: 0021-4922 *the whole document*.
<i>TJ</i>	AJ	NAKURA T. ET AL: "A hydrogen-barrier interlayer dielectric with a Si02/SiON/Si02 stacked film for logic-embedded FeRAMs" ELECTRON DEVICES MEETING, 1999. IEDM TECHNICAL DIGEST. INTERNATIONAL WASHINGTON, DC, USA 5-8 DEC. 1999, PISCATAWAY, NJ, USA, IEEE, US, 5 December 1999 (1999-12-05), pages 801-804, XP010372095 ISBN: 0-7803-5410-9 *the whole document*.
<i>TJ</i>	AK	Partial European Search Report dated 10/24/05.

Examiner

Date Considered

*10/26/05*



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#### U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
TB	AA	6,509,601	Lee et al.	1/21/03	257	310
	AB					
	AC					
	AD					
	AE					

#### FOREIGN PATENT DOCUMENTS

Document No.	Date	Country	Translation (Yes or No)
AF 2001-111007	4/20/01	Japan	No
AG			
AH			
AI			
AJ			

#### OTHER DOCUMENTS

TB	AK	Japanese Office Action dated 2/7/06.
	AL	
Examiner	<i>D. S. Boz</i>	Date Considered 4/26/06

<b>INFORMATION DISCLOSURE CITATION PTO-1449</b>	Atty. Docket No. 021557A	Serial No. 10/697,944
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	Filing Date: October 31, 2003	Group Art Unit: 2811

**U.S. PATENT DOCUMENTS**

Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
<i>DS</i>	AA					
	AB					
	AC					
	AD					
	AE					

**FOREIGN PATENT DOCUMENTS**

	Document No.	Date	Country	Translation (Yes or No)
<i>T2</i>	AF EP 1 077 483 A	2/21/01	Europe	Yes
	AG			
	AH			
	AI			
	AJ			

**OTHER DOCUMENTS**

<i>DS</i>	AK	European Search Report of 3/27/06.
	AL	
Examiner <i>DS 2/21/02</i>	Date Considered	<i>4/18/06</i>